						_		_
Form PTO 1449 (Modified)		U.S. DEPARTMEN PATENT AND TR	IT OF COMMERCE ADEMARK OFFICE			SERIAL		
				286321US0PC1	10/568,582			
LIST OF	REFE	ERENCES CITED BY A	PPLICANT	APPLICANT Takashi KIKUKAWA, et al.				
				FILING DATE		GROUP		
				February 17, 2006		2627		
				U.S. PATENT DOCUMENTS		2627		
EXAMINER	_	DOCUMENT		U.S. PATENT DOCUMENTS		T		_
INITIAL	AA	NUMBER	DATE	NAME	CLASS	SUB	FILING DATE IF APPROPRIATE	Ξ
	AB	+	+		+			_
<del></del>	AC	+	-	<del> </del>	+	'		_
	AD		+		<del> </del>	<u> </u>		_
	AC	+	+	<del> </del>	-			
	AF		+					_
	AC	<del> </del>	+			<b></b>		_
	AH		+			$\vdash$		_
	Al		+	<del> </del>		$\vdash$		_
	AJ		+	<u> </u>		<b> </b>		_
	AK	<del></del>	+	<del></del>	ـــ	$\vdash$		_
	AL	+	+			$\vdash$		_
	AM	<del></del>	+		+	-		_
	AN		+	+		-	<del></del>	_
			E0	PREIGN PATENT DOCUMENTS	لــــــــــــــــــــــــــــــــــــــ			_
		Τ		TEIGN PAIENT DOCUMENTS				
A.107		DOCUMENT NUMBER	DATE	COUNTRY		YES	TRANSLATION NO	
/MB/	AO	EP 1 645 429 A1	4/12/2006	Europe				_
/MB/	AR	EP 1 646 042 A1	4/12/2006	Europe				_
/MB/	AO	EP 1 640 977 A1	3/29/2006	Europe				
/MB/	AR	EP 1 640 981 A1	3/29/2006	Europe				
/MB/	AS	EP 1 657 717 A1	5/17/2006	Europe				_
/IVID/	AT	EP 1 643 497 A1	4/5/2006	Europe				Ξ
	AU							_
	ΑV							_
		OTHER RE	EFERENCES (I	Including Author, Title, Date, Pertinent	t Pages, et	c.)		Т
/MB/	AW	Wei-Chi HSU, et al., "Blue-Laser Readout Properties of Super Resolution Near Field Structure Disc with Inorganic Write- Once Recording Layer", JPN. J. APPL. PHYS, XP002458621, vol. 42, no. part 1, 2B, February 2003, pages 1005-1009						
/MB/	AX	Jooho KIM, et al., "Reactive recording with rare-earth transition metal", APPLIED PHYSICS LETTERS, XP012029161, vol. 79, no. 16, October 15, 2001, pages 2600-2602						
/MB/	AY	Takashi KiKUKAWA, et al., "Recording and Readout Mechanisms of Super Resolution Near-Field Structure Disc with Silver- Oxide Layer", JPN. J. APPL. PHYS., XP002452548, vol. 42, no. 28, February 2003, pages 1038-1039						
	AZ				Additi	ional Refer	rences sheet(s) attach	ed
Examiner		/Mark Bloui	in/		Date Considered 08/07/2008		-	
*Examiner: Ini conformance :	tial if re	aference is considered, at considered, include or	whether or not opy of this form	citation is in conformance with MPEP 60 with next communication to applicant.	9; Draw lin-	e through	citation if not in	_